1. A method of rendering a three-dimensional model, comprising:

obtaining a characteristic of the three-dimensional model;

determining a three-dimensional dither pattern based on

5 the characteristic; and

rendering the three-dimensional model using the three-dimensional dither pattern.

2. The method of claim 1, wherein determining comprises

10 selecting a number of points to make up the three-dimensional dither pattern and a location of the points on the three-dimensional model.

3. The method of claim 1, wherein the characteristic is

15 obtained for a region of the three-dimensional model, and the three-dimensional dither pattern is determined for the region.

4. The method of claim 3, wherein characteristics are obtained for different regions of the three-dimensional model,

20 different three-dimensional dither patterns are determined for the different regions based on the characteristics for the different regions, and the three-dimensional model is rendered using the different three-dimensional dither patterns.

5. The method of claim 1, wherein the three-dimensional dither pattern comprises data specifying pixels to illuminate when rendering the three-dimensional model.

6. The method of claim 5, wherein the pixels define individual points in the three-dimensional dither pattern.

7. The method of claim 1, wherein the characteristic comprises a density of the three-dimensional model.

8. The method of claim 7, wherein the density is obtained for a three-dimensional region of the three-dimensional model by averaging densities of sub-regions within the three-dimensional region.

9. The method of claim 1, wherein the characteristic comprises one of a color of the three-dimensional model, a field strength in the three-dimensional model, a temperature in the three-dimensional model, and a pollution concentration in the three-dimensional model.

10. The method of claim 1, wherein determining the three-dimensional dither pattern comprises selecting the three-dimensional dither pattern from a number of three-dimensional dither patterns stored in memory.

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11. An article comprising a machine-readable medium that stores executable instructions for rendering a three-dimensional model, the instructions causing a machine to:

obtain a characteristic of the three-dimensional model;

10 determine a three-dimensional dither pattern based on the characteristic; and

render the three-dimensional model using the three-dimensional dither pattern.

15 12. The article of claim 11, wherein determining comprises selecting a number of points to make up the three-dimensional dither pattern and a location of the points on the three-dimensional model.

20 13. The article of claim 11, wherein the characteristic is obtained for a region of the three-dimensional model, and the three-dimensional dither pattern is determined for the region.

14. The article of claim 13, wherein characteristics are obtained for different regions of the three-dimensional model, different three-dimensional dither patterns are determined for the different regions based on the characteristics for the different regions, and the three-dimensional model is rendered using the different three-dimensional dither patterns.

15. The article of claim 11, wherein the three-dimensional dither pattern comprises data specifying pixels to illuminate when rendering the three-dimensional model.

16. The article of claim 15, wherein the pixels define individual points in the three-dimensional dither pattern.

17. The article of claim 11, wherein the characteristic comprises a density of the three-dimensional model.

18. The article of claim 17, wherein the density is obtained for a three-dimensional region of the three-dimensional model by averaging densities of sub-regions within the three-dimensional region.

19. The article of claim 11, wherein the characteristic comprises one of a color of the three-dimensional model, a field strength in the three-dimensional model, a temperature in the three-dimensional model, and a pollution concentration in the three-dimensional model.

20. The article of claim 11, wherein determining the three-dimensional dither pattern comprises selecting the three-dimensional dither pattern from a number of three-dimensional dither patterns stored in memory.

21. An apparatus for rendering a three-dimensional model, comprising:

a memory that stores executable instructions; and

a processor that executes the instructions to:

obtain a characteristic of the three-dimensional model;

determine a three-dimensional dither pattern based on the characteristic; and

render the three-dimensional model using the three-dimensional dither pattern.

22. The apparatus of claim 21, wherein determining comprises selecting a number of points to make up the three-dimensional dither pattern and a location of the points on the three-dimensional model.

23. The apparatus of claim 21, wherein the characteristic is obtained for a region of the three-dimensional model, and the three-dimensional dither pattern is determined for the region.

24. The apparatus of claim 23, wherein characteristics are obtained for different regions of the three-dimensional model, different three-dimensional dither patterns are determined for the different regions based on the characteristics for the different regions, and the three-dimensional model is rendered using the different three-dimensional dither patterns.

25. The apparatus of claim 21, wherein the three-dimensional dither pattern comprises data specifying pixels to illuminate when rendering the three-dimensional model.

26. The apparatus of claim 25, wherein the pixels define individual points in the three-dimensional dither pattern.

27. The apparatus of claim 21, wherein the

5 characteristic comprises a density of the three-dimensional model.

28. The apparatus of claim 27, wherein the density is obtained for a three-dimensional region of the three-

10 dimensional model by averaging densities of sub-regions within the three-dimensional region.

29. The apparatus of claim 21, wherein the characteristic comprises one of a color of the three-

15 dimensional model, a field strength in the three-dimensional model, a temperature in the three-dimensional model, and a pollution concentration in the three-dimensional model.

30. The apparatus of claim 21, wherein determining the

20 three-dimensional dither pattern comprises selecting the three-dimensional dither pattern from a number of three-dimensional dither patterns stored in memory.